



THE AMERICAN ASSOCIATION FOR  
LABORATORY ACCREDITATION

## ACCREDITED LABORATORY

A2LA has accredited

**SSC LAB DIVISION**

**Little Rock, AR**

for technical competence in the field of **Calibration**

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 *General Requirements for the Competence of Testing and Calibration Laboratories*. This laboratory also meets the requirements of ANSI/NCSL Z540-1-1994 and any additional program requirements in the field of calibration. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (*refer to joint ISO-ILAC-IAF Communiqué dated 18 June 2005*).

Presented this 11<sup>th</sup> day of April 2007.

A handwritten signature in cursive script, reading "Peter Meyer", written over a horizontal line.

President  
For the Accreditation Council  
Certificate Number 1754.01  
Valid to April 30, 2009  
Revised: March 27, 2009



For the calibrations to which this accreditation applies, please refer to the laboratory's Calibration Scope of Accreditation.

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005  
& ANCI/NCSL Z540-1-1994

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CALIBRATION

Valid To: April 30, 2009

Certificate Number: 1754.01

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following calibrations<sup>1</sup>:

I. Electrical – DC & Low Frequency<sup>5,6</sup>

Parameter/Equipment	Range	Best Uncertainty <sup>2,3</sup> (±)		Comments
		Laboratory	On-Site	
DC Voltage – Measure	(10 to 100) mV (0.1 to 1) V (1 to 10) V (10 to 100) V (0.1 to 1) kV	7 μV/V + 3 μV 6 μV/V + 0.3 μV 6 μV/V + 0.05 μV 8 μV/V + 0.3 μV 18 μV/V + 0.1 μV	See Note 4	HP 3458A Opt. 002
DC Voltage – Generate	(0 to 320) mV (0.3 to 3.2) V (3.2 to 32) V (32 to 320) V (320 to 1050) V	60 μV/V + 4 μV 60 μV/V + 40 μV 60 μV/V + 420 μV 60 μV/V + 4.5 mV 60 μV/V + 20 mV	See Note 4	Wavetek 9100 with Opt 100/600
DC Current – Measure	(10 to 100) μA (0.1 to 10) mA (10 to 100) mA (0.1 to 1) A	25 μA/A + 8 μA 25 μA/A + 5 μA 40 μA/A + 5 μA 0.012 % + 10 μA	See Note 4	HP 3458A Opt. 002
DC Current – Generate	(0 to 320) μA (0.32 to 3.2) mA (3.2 to 32) mA (32 to 320) mA (0.32 to 3.2) A (3.2 to 10.5) A (10.5 to 20) A	0.01 % + 10 nA 0.01 % + 80 nA 0.01 % + 900 nA 0.02 % + 9.6 μA 0.06 % + 120 μA 0.06 % + 940 μA 0.06 % + 4.5 mA	See Note 4	Wavetek 9100 with Opt 100/600

Parameter/Equipment	Range	Best Uncertainty <sup>2,3</sup> (±)		Comments
		Laboratory	On-Site	
Resistance – Measure	(1 to 10) Ω (10 to 100) Ω (0.1 to 100) kΩ (0.1 to 1) MΩ (1 to 10) MΩ (10 to 100) MΩ (0.1 to 1) GΩ	18 μΩ/Ω + 0.05 mΩ 15 μΩ/Ω + 0.5 mΩ 13 μΩ/Ω + 0.05 Ω 18 μΩ/Ω + 2 Ω 50 μΩ/Ω + 100 Ω 0.050 % + 1 kΩ 0.5 % + 10 kΩ	See Note 4	HP 3458A with Opt 002; 4-wire measurement
Resistance – Generate	(0 to 40) Ω (40 to 400) Ω (0.4 to 4) kΩ (4 to 40) kΩ (40 to 400) kΩ (0.4 to 4) MΩ (4 to 40) MΩ (40 to 400) MΩ	0.05 % + 20 mΩ 0.02 % + 20 mΩ 0.02 % + 80 mΩ 0.02 % + 800 mΩ 0.02 % + 8 Ω 0.02 % + 100 Ω 0.05 % + 2 kΩ 0.06 % + 40 kΩ	See Note 4	Wavetek 9100 with Opt 100/600

Parameter/Range	Frequency	Best Uncertainty <sup>2,3</sup> (±)		Comments
		Laboratory	On-Site	
AC Voltage – Measure				
(10 to 100) mV	(1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz	0.03 % + 4 μV 0.02 % + 2 μV 0.03 % + 2 μV 0.1 % + 2 μV 0.5 % + 2 μV 4 % + 10 μV	See Note 4	HP 3458A with Opt 002
100 mV to 10 V	(1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (0.3 to 1) MHz (1 to 2) MHz	70 μV/V + 0.4 mV 70 μV/V + 0.2 mV 0.01 % + 0.2 mV 0.03 % + 0.2 mV 0.08 % + 0.2 mV 0.3 % + 1 mV 1 % + 1 mV 1.5 % + 1 mV		
(10 to 100) V	(1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (0.3 to 1) MHz	0.02 % + 4 mV 0.02 % + 2 mV 0.02 % + 2 mV 0.04 % + 2 mV 0.12 % + 2 mV 0.4 % + 10 mV 1.5 % + 10 mV		

Parameter/Range	Frequency	Best Uncertainty <sup>2,3</sup> (±)		Comments
		Laboratory	On-Site	
AC Voltage – Measure (cont.)  (100 to 1000) V	(1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz	0.04 % + 40 µV 0.04 % + 20 µV 0.06 % + 20 µV 0.1 % + 20 µV 0.3 % + 20 µV	See Note 4	HP 3458A with Opt 002
AC Voltage – Generate  (0 to 10) mV  (10 to 32) mV  (32 to 320) mV  (0.32 to 3.2) V  (3.2 to 32) V  (32 to 105) V	10 Hz to 3 kHz (3 to 10) kHz (10 to 30) kHz (30 to 50) kHz (50 to 100) kHz  10 Hz to 3 kHz (3 to 10) kHz (10 to 30) kHz (30 to 50) kHz (50 to 100) kHz  10 Hz to 3 kHz (3 to 10) kHz (10 to 30) kHz (30 to 50) kHz (50 to 100) kHz  10 Hz to 3 kHz (3 to 10) kHz (10 to 30) kHz (30 to 50) kHz (50 to 100) kHz  10 Hz to 3 kHz (3 to 10) kHz (10 to 30) kHz (30 to 50) kHz (50 to 100) kHz	0.04 % + 380 µV 0.04 % + 510 µV 0.06 % + 960 µV 0.09 % + 1 mV 0.2 % + 5 mV  0.04 % + 100 µV 0.04 % + 130 µV 0.06 % + 240 µV 0.09 % + 480 µV 0.2 % + 1 mV  0.04 % + 20 µV 0.04 % + 30 µV 0.05 % + 50 µV 0.09 % + 100 µV 0.2 % + 260 µV  0.04 % + 190 µV 0.04 % + 260 µV 0.06 % + 480 µV 0.09 % + 960 µV 0.2 % + 2 mV  0.04 % + 2 mV 0.07 % + 3 mV 0.08 % + 5 mV 0.2 % + 10 mV 0.4 % + 30 mV  0.04 % + 6 mV 0.06 % + 8 mV 0.09 % + 20 mV 0.2 % + 30 mV 0.4 % + 10 mV	See Note 4	Wavetek 9100 with Opt 100/600

Parameter/Range	Frequency	Best Uncertainty <sup>2,3</sup> (±)		Comments
		Laboratory	On-Site	
AC Voltage – Generate (cont.)				
(105 to 320) V	(40 to 100) Hz (0.1 to 1) kHz (1 to 3) kHz (3 to 10) kHz (10 to 20) kHz (20 to 30) kHz	0.05 % + 20 mV 0.05 % + 20 mV 0.08 % + 20 mV 0.08 % + 30 mV 0.1 % + 50 mV 0.2 % + 60 mV	See Note 4	Wavetek 9100 with Opt 100/600
(320 to 800) V	(40 to 100) Hz (0.1 to 1) kHz (1 to 3) kHz (3 to 10) kHz (10 to 20) kHz (20 to 30) kHz	0.05 % + 60 mV 0.05 % + 60 mV 0.08 % + 60 mV 0.08 % + 100 mV 0.1 % + 160 mV 0.2 % + 210 mV		
(320 to 1050) V	(40 to 100) Hz (0.1 to 1) kHz (1 to 3) kHz (3 to 10) kHz (10 to 20) kHz	0.05 % + 130 mV 0.05 % + 130 mV 0.04 % + 130 mV 0.08 % + 210 mV 0.1 % + 320 mV		

Parameter	Range	Best Uncertainty <sup>2,3</sup> (±)		Comments
		Laboratory	On-Site	
Oscilloscope –				
Square Function –				
Into 50 Ω	4.440 mV to 3.3360 V	0.25 %	See Note 4	Wavetek 9100 with Opt 100/600
Into 1 MΩ	4.440 mV to 1.3344 V	0.25 %		
DC Function –				
Into 50 Ω	4.440 mV to 2.780 V -4.440 mV to -2.78 V	0.2 % + 40 μV 0.2 % + 40 μV		
Into 1 MΩ	4.440 mV to 2.780 V -4.440 mV to -2.78 V	0.2 % + 40 μV 0.2 % + 40 μV		
Sine Function –				
Into 1 MΩ	4.440 mV to 133.44 V	0.25 %		
Into 50 Ω	4.440 mV to 5.6 V	0.25 %		
Into 50 Ω	10.656 mV to 5.560 V	1.5 %		

Parameter	Range	Best Uncertainty <sup>2,3</sup> (±)		Comments
		Laboratory	On-Site	
Oscilloscope <sup>8</sup> (cont.) – Edge Function – Into 50 Ω Into 1 MΩ Markers Function 600 Band Width – Into 50 Ω	88.8 mV to 1.112 V 888.0 mV to 55.6 V  2.00 ns to 5.5 s	3 % 3 %  25 ppm	See Note 4	Wavetek 9100 with Opt 100/600

Parameter/Range	Frequency	Best Uncertainty <sup>2,3</sup> (±)		Comments
		Laboratory	On-Site	
AC Current – Measure  (10 to 100) μA  (0.1 to 100) mA  (0.1 to 1) A	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz  (10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (0.1 to 5) kHz (5 to 20) kHz (20 to 50) kHz (50 to 100) kHz  (10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (0.1 to 5) kHz (5 to 20) kHz (20 to 50) kHz	0.4 % + 0.03 μA 0.2 % + 0.03 μA 0.04 % + 0.03 μA  0.4 % + 20 μA 0.2 % + 20 μA 0.1 % + 20 μA 0.03 % + 20 μA 0.06 % + 20 μA 0.4 % + 40 μA 0.6 % + 200 μA  0.4 % + 0.2 mA 0.2 % + 0.2 mA 0.1 % + 0.2 mA 0.1 % + 0.2 mA 0.3 % + 0.2 mA 1 % + 0.4 mA	See Note 4	HP 3458A with Opt 002
Electrical Calibration of Optical Tachometers –  (1 to 10 000) rpm	0.5 Hz to 10 MHz	0.25 parts in 10 <sup>6</sup>	See Note 4	Wavetek 9100 with/opt 100/600

Parameter/Range	Frequency	Best Uncertainty <sup>2,3</sup> (±)		Comments
		Laboratory	On-Site	
AC Current – Generate				
(0 to 32) µA	10 Hz to 3 kHz (3 to 10) kHz (10 to 20) kHz (20 to 30) kHz	0.07 % + 900 nA 0.1 % + 2 µA 0.2 % + 6 µA 0.2 % + 9 µA	See Note 4	Wavetek 9100 with Opt 100/600
(32 to 320) µA	10 Hz to 3 kHz (3 to 10) kHz (10 to 20) kHz (20 to 30) kHz	0.07 % + 300 nA 0.1 % + 600 nA 0.2 % + 2 µA 0.2 % + 3 µA		
(0.32 to 3.2) mA	10 Hz to 3 kHz (3 to 10) kHz (10 to 20) kHz (20 to 30) kHz	0.07 % + 300 nA 0.1 % + 600 nA 0.2 % + 2 µA 0.2 % + 3 µA		
(3.2 to 32) mA	10 Hz to 3 kHz (3 to 10) kHz (10 to 20) kHz (20 to 30) kHz	0.08 % + 3.2 µA 0.1 % + 6.4 µA 0.2 % + 13 µA 0.25 % + 23 µA		
(32 to 320) mA	10 Hz to 3 kHz (3 to 10) kHz (10 to 20) kHz (20 to 30) kHz	0.1 % + 32 µA 0.25 % + 48 µA 0.2 % + 64 µA 0.25 % + 96 µA		
(0.32 to 3.2) A	10 Hz to 3 kHz (3 to 10) kHz	0.1 % + 480 µA 0.25 % + 2.6 mA		
(3.2 to 10.5) A	10 Hz to 3 kHz (3 to 10) kHz	0.2 % + 3 mA 0.5 % + 10 mA		
(10.5 to 20) A	10 Hz to 3 kHz (3 to 10) kHz	0.2 % + 6.9 mA 0.5 % + 23 mA		
(3.2 to 32) A	(10 to 100) Hz (100 to 440) Hz	0.2 % + 5.5 mA 0.78 % + 27 mA		
(32 to 200) A	(10 to 100) Hz (100 to 440) Hz	0.21 % + 90 mA 0.67 % + 0.25 A		
(16 to 160) A	(10 to 100) Hz	0.2 % + 28 mA		
(160 to 1000) A	(10 to 100) Hz	0.21 % + 0.45 A		

Parameter/Equipment	Range	Best Uncertainty <sup>2,3</sup> (±)		Comments
		Laboratory	On-Site	
Electrical Calibration of Thermocouple Indicators –				
Type B	500 °C to 800 °C 800 °C to 1000 °C 1000 °C to 1400 °C 1400 °C to 1820 °C	0.55 °C 0.41 °C 0.34 °C 0.37 °C	See Note 4	Wavetek 9100 with opt 100/600
Type C	0 °C to 600 °C 600 °C to 1000 °C 1000 °C to 1800 °C 1800 °C to 2320 °C	0.29 °C 0.27 °C 0.4 °C 0.41 °C		
Type J	-210 °C to -100 °C -100 °C to 800 °C 800 °C to 1000 °C 1000 °C to 1200 °C	0.25 °C 0.19 °C 0.21 °C 0.23 °C		
Type K	-250 °C to -200 °C -200 °C to -100 °C -100 °C to 100 °C 100 °C to 600 °C 600 °C to 1372 °C	0.57 °C 0.27 °C 0.19 °C 0.23 °C 0.27 °C		
Type R	0 °C to 100 °C 100 °C to 200 °C 200 °C to 1600 °C 1600 °C to 1767 °C	0.52 °C 0.4 °C 0.35 °C 0.28 °C		
Type S	0 °C to 200 °C 200 °C to 1000 °C 1000 °C to 1400 °C 1400 °C to 1767 °C	0.49 °C 0.37 °C 0.35 °C 0.36 °C		
Type T	-250 °C to -200 °C -200 °C to -100 °C -100 °C to 0 °C 0 °C to 400 °C	0.59 °C 0.27 °C 0.22 °C 0.17 °C		

II. Dimensional

Parameter/Equipment	Range	Best Uncertainty <sup>2,3,7</sup> (±)		Comments
		Laboratory	On-Site	
Angle Blocks	0° to 45°	140 μin	Not Available	Height gage, sine plate and gage blocks
Gage Blocks	(0 to 4) in	(4.3 + 1.2L) μin	Not Available	By mechanical comparison
Plain Ring Gages	(0.04 to 12) in	(24 + 0.75L) μin	Not Available	LabMaster laser measuring system
Plug Gages	(0 to 14) in	(12 + 0.5L) μin	Not Available	LabMaster laser measuring system
Reference Spheres	(0 to 2) in	12 μin	Not Available	LabMaster laser measuring system
Pin Gages	Up to 1 in	12 μin	Not Available	LabMaster laser measuring system
Indicators	Up to 5 in	30 μin	(29 + 110L) μin	Gage blocks
Micrometers and Depth Micrometers	(0 to 12) in	(29 + 0.34L) μin	(210 + 3.4L) μin	Gage blocks
Calipers	(0 to 40) in	290 μin	(290 + 6.5L) μin	Gage blocks
Height Gages	(0 to 40) in	(29 + 0.78L) μin	(6.9 + 12L) μin	Gage blocks
Optical Comparators – Linearity Squareness	Up to 16 in	210 μin 240 μin	530 μin 290 μin	Inspection master
Precision Rules	(6 to 72) in	0.0062 in	Not Available	Precision rule and microscope

Parameter/Equipment	Range	Best Uncertainty <sup>2,3,7</sup> (±)		Comments
		Laboratory	On-Site	
Surface Plate Flatness	Up to 72 in x 144 in	Not Available	$4.7\sqrt{(D/4)} \mu\text{in}$	Electronic leveling system  Uncertainty is to be no less than the acceptable closure error for the procedure
60° Thread Plugs – Pitch Diameter	Up to 2 in	69 $\mu\text{in}$	Not Available	3-wire measurement
Thread Wires	Up to 0.3 in	12 $\mu\text{in}$	Not Available	LabMaster laser measuring system
Angle	0° to 90°	150 $\mu\text{in}$	Not Available	Optical comparator

### III. Mechanical

Parameter/Equipment	Range	Best Uncertainty <sup>2,3</sup> (±)		Comments
		Laboratory	On-Site	
Vacuum	Up to 26 inHg	0.042%	0.042 %	Transducer
Balances	(0 to 20) g (0 to 200) g (0 to 1000) g (0 to 2000) g (0 to 5000) g (0 to 10 000) g	0.58 mg 2.3 mg 12 mg 29 mg 470 mg 1.1 mg	See Note 4	NIST Handbook 44; verification with class F1 weights
Torque – Transducers	(0 to 1000) ft·lb	0.058 ft·lb	0.5 %	Deadweights and torque arm
Wrenches	(0 to 1000) ft·lb	12 ft·lb	1 %	Torque transducer

Parameter/Equipment	Range	Best Uncertainty <sup>2,3</sup> (±)		Comments
		Laboratory	On-Site	
Force – Compression & Tension	(0 to 100 000) lbf	0.25 %	0.25 %	ASTM E4, with load cells
Scales	(0 to 10) lb (0 to 20) lb (0 to 50) lb (0 to 500) lb (0 to 1000) lb (0 to 5000) lb (0 to 100 000) lb	0.0025 lb 0.005 lb 0.013 lb 0.024 lb 0.12 lb 1.5 lb 21 lb	See Note 4	NIST Handbook 44; verification with class F1 weights
Pressure Gauges – Oil	Up to 10 000 psi	0.6 %	5.9 psi	Dead weight tester transducer
Air	Up to 300 psi Up to 50 inH <sub>2</sub> O Up to 100 psi Up to 300 psi	0.042 % 0.02 inH <sub>2</sub> O 0.03 % 0.09 %	0.042 psi	Transducer Transducer
Mass	Up to 210 g	0.3 mg	Not Available	Read on balance standardized with class E2 weights.
Indirect Verification of Brinell Hardness Testers	(72 to 277) HBS	Not Available	3.4 HBS	ASTM E10

Parameter/Equipment	Range	Best Uncertainty <sup>2,3</sup> (±)		Comments
		Laboratory	On-Site	
Indirect Verification of Rockwell and Rockwell Superficial Hardness Testers	HRA:	Not Available		ASTM E18
	Low		0.37	
	Middle		0.37	
	High		0.27	
	HRB:			
	Low		0.53	
	Middle		0.32	
	High		0.32	
	HRC:			
	Low		0.38	
	Middle		0.38	
	High		0.29	
	HRE:			
	Low		0.53	
	Middle		0.53	
	High		0.53	
	HR15N:			
	Low		0.57	
	Middle		0.57	
	High		0.27	
	HR30N:			
	Low		0.41	
	Middle		0.41	
	High		0.41	
	HR45N			
	Low		0.51	
	Middle		0.51	
	High		0.51	
HR15T:				
Low	0.49			
Middle	0.41			
High	0.41			
HR30T:				
Low	0.43			
Middle	0.37			
High	0.37			

Parameter/Equipment	Range	Best Uncertainty <sup>2,3</sup> (±)		Comments
		Laboratory	On-Site	
Direct Verification of Durometers (type A & type D)			Not Available	ASTM D2240
Verification of indenter shape and extension:				
Extension at zero reading	----	0.0023 <i>D</i>		The dimensional characteristics of the indenters are verified by optical projection.
Verification of the durometer spring	Type A, B, E, O Type D, C, DO	0.76 <i>D</i> 0.76 <i>D</i>		The durometer spring is verified with deadweights. This best uncertainty applies to all durometer types.

#### IV. Thermodynamic

Parameter/Equipment	Range	Best Uncertainty <sup>2,3</sup> (±)		Comments
		Laboratory	On-Site	
Infrared	Up to 500 °C Up to 1200 °C	1.2 °C 1.7 °C	See Note 4	Black body and dry well
Relative Humidity –  Fixed Points NaCl LiCl	  75.5 % 11.3 %	  2.2 % 2.1 %	See Note 4	ASTM E104 with salts

#### V. Chemical

Parameter/Equipment	Range	Best Uncertainty <sup>2,3</sup> (±)		Comments
		Laboratory	On-Site	
PH Meters	(4.0, 7.0, 10.0) units	0.012 pH	0.12 pH	NIST Traceable

Parameter/Equipment	Range	Best Uncertainty <sup>2,3</sup> (±)		Comments
		Laboratory	On-Site	
Conductivity	10 µS (10 to 1000) µS (1000 to 10 000) µS	0.5 µS 2.3 µS 320 µS	See Note 4	Traceable conductivity standard fluid

## VI. Time and Frequency

Parameter/Equipment	Range	Best Uncertainty <sup>2,3</sup> (±)		Comments
		Laboratory	On-Site	
Frequency	1 Hz to 120 MHz	2.2 parts in 10 <sup>11</sup>	Not Available	GPS with 24 hour averaging

<sup>1</sup> This laboratory offers commercial and on-site calibration services.

<sup>2</sup> “Best Uncertainty” is the smallest uncertainty of measurement that a laboratory can achieve within its scope of accreditation when performing more or less routine calibrations of nearly ideal measurement standards of nearly ideal measuring equipment. Best uncertainties represent expanded uncertainties expressed at approximately the 95 % level of confidence, usually using a coverage factor of  $k = 2$ . The best uncertainty of a specific calibration performed by the laboratory may be greater than the best uncertainty due to the behavior of the customer’s device, to the environment (if the calibration is performed in the field) and to influences from the circumstances of the specific calibration.

<sup>3</sup> On-site calibration service is available for this calibration. The uncertainties achievable on a customer's site can normally be expected to be larger than the Best Measurement Capabilities (BMC) that the accredited laboratory has been assigned as Best Uncertainty on the A2LA Scope. Allowance must be made for aspects such as the environment at the place of calibration and for other possible adverse effects such as those caused by transportation of the calibration equipment. The usual allowance for the uncertainty introduced by the item being calibrated, (e.g. resolution) must also be considered and this, on its own, could result in the calibration uncertainty being larger than the BMC.

<sup>4</sup> The best uncertainty stated for calibrations performed in the laboratory is applicable for calibrations performed on-site.

<sup>5</sup> The measurands stated are measured with the HP 3458A. This capability is suitable for the calibration of the devices intended to generate the measurand in the ranges indicated. Best measurement uncertainties are expressed as either a specific value that covers the full range or as a combination of the percent or portion of the reading plus a fixed floor specification.

<sup>6</sup> The measurands stated are generated with the Wavetek 9100. This capability is suitable for the calibration of the devices intended to measure the stated measurand in the ranges indicated. Best measurement uncertainties are expressed as either a specific value that covers the full range or as a combination of the percent or portion of the reading plus a fixed floor specification.

<sup>7</sup> In the statement of best uncertainty,  $L$  is the numerical value of the nominal length of the device measured in inches;  $D$  is the numerical value of the diagonal in inches.

<sup>8</sup> Where “ppm” appears in the best measurement uncertainty, it is equivalent to that part in one million.